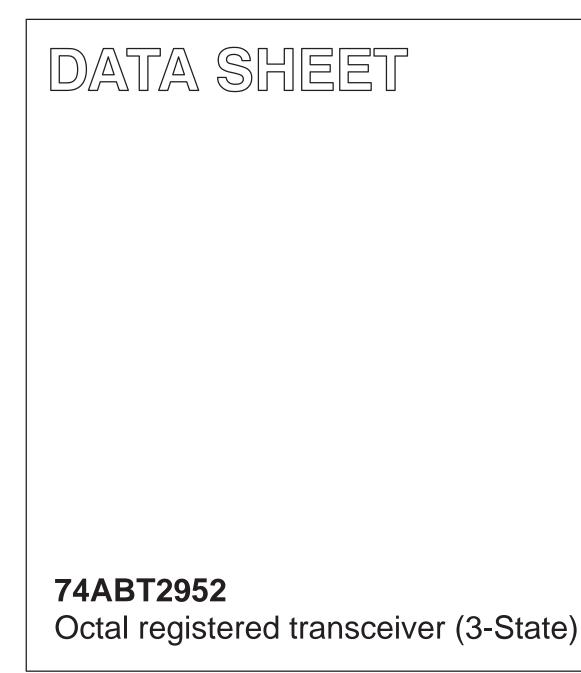
INTEGRATED CIRCUITS



Product specification Supersedes data of 1995 Jun 15 IC23 Data Handbook

1998 Feb 11





74ABT2952

FEATURES

- 8-bit registered transceiver
- Independent registers for A and B buses
- Output capability: +64mA/-32mA
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model
- Power-up 3-State
- Power-up reset
- Live insertion/extraction permitted

DESCRIPTION

The 74ABT2952 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT2952 device is an 8-bit registered transceiver. Two 8-bit back-to-back registers store data flowing in both directions between two bidirectional buses. Data applied to the inputs is entered and stored on the rising edge of the Clock (CPXX) provided that the Clock Enable (CEXX) is Low. The data is then present at the 3-State output buffers, but is only accessible when the Output Enable (\overline{OEXX}) is Low. Data flow from A inputs to B outputs is the same as for B inputs to A outputs.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay CPBA to An or CPAB to Bn	C _L = 50pF; V _{CC} = 5V	5.7	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	4	pF
C _{I/O}	I/O capacitance	Outputs disabled; $V_O = 0V$ or V_{CC}	7	pF
I _{CCZ}	Total supply current	Outputs disabled; V_{CC} =5.5V	110	μΑ

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	TEMPERATURE RANGE OUTSIDE NORTH AMERICA		DWG NUMBER	
24-Pin Plastic DIP	–40°C to +85°C	74ABT2952 N	74ABT2952 N	SOT222-1	
24-Pin plastic SO	–40°C to +85°C	74ABT2952 D	74ABT2952 D	SOT137-1	
24-Pin Plastic SSOP Type II	–40°C to +85°C	74ABT2952 DB	74ABT2952 DB	SOT340-1	
24-Pin Plastic TSSOP Type I	-40°C to +85°C	74ABT2952 PW	7ABT2952PW DH	SOT355-1	

PIN CONFIGURATION

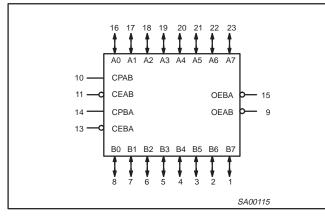
B7 1 24 V _{CC}	
B6 2 23 A7	
B5 3 22 A6	
B4 4 21 A5	
B3 5 20 A4	
B2 6 19 A3	
B1 7 18 A2	
B0 8 17 A1	
OEAB 9 16 A0	
CPAB 10 15 OEBA	
СЕАВ 11 14 СРВА	
GND 12 13 CEBA	

PIN DESCRIPTION

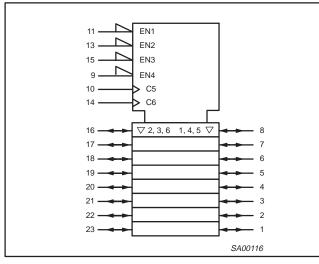
PIN NUMBER	SYMBOL	NAME AND FUNCTION
10, 14	CPAB / CPBA	Clock input A to B / Clock input B to A
11, 13	CEAB / CEBA	Clock enable input A to B / Clock enable input B to A
16, 17, 18, 19, 20, 21, 22, 23	A0 – A7	Data inputs/outputs (A side)
1, 2, 3, 4, 5, 6, 7, 8	B0 – B7	Data outputs/outputs (B side)
9, 15	OEAB / OEBA	Output enable inputs
12	GND	Ground (0V)
24	V _{CC}	Positive supply voltage

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LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE for Register An or Bn

I	NPUTS		INTERNAL	OPERATING		
An or Bn	СРХХ	CEXX	Q	MODE		
Х	Х	н	NC	Hold data		
L H	$\uparrow \uparrow$	L	L H	Load data		

H = High voltage level

L = Low voltage level $\uparrow = Low-to-High transition$

X = Don't care

X = AB or BA

NC=No change

FUNCTION TABLE for Output Enable

INPUTS	INTERNAL	An or Bn	OPERATING	
OEXX	Q	OUTPUTS	MODE	
н	Х	Z	Disable outputs	
L	L H	L H	Enable outputs	

H = High voltage level

L = Low voltage level

X = Don't care

XX = AB or BA

Z = High impedance "off" state

ABSOLUTE MAXIMUM RATINGS ^{1, 2}	
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SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
Ι _{ΟΚ}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	128	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

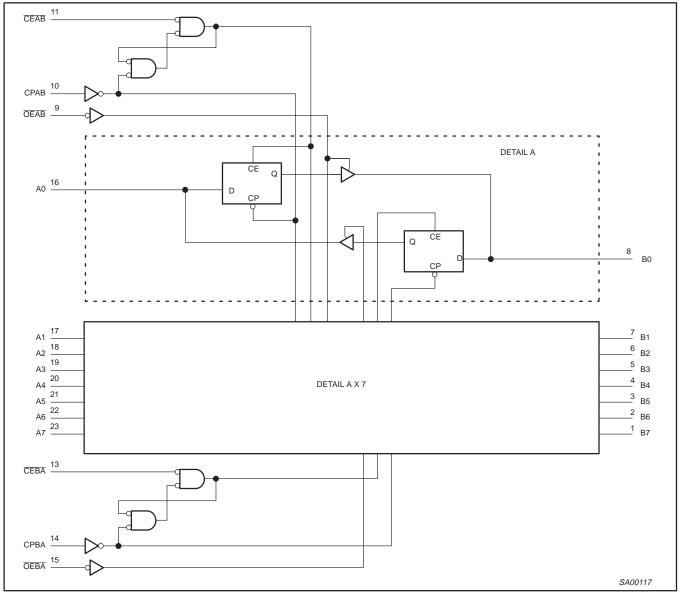
2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction

temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C. 3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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Product specification

LOGIC DIAGRAM



RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
STWBOL	PARAMETER	Min	Max	UNIT
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level Input voltage		0.8	V
I _{ОН}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
Δt/Δv	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

					LIMITS					
SYMBOL	PARAMETER		TEST CONDITIONS		T _{amb} = +25°C			–40°C 85°C		
					Тур	Max	Min	Max		
VIK	Input clamp vol	age	$V_{CC} = 4.5V; I_{IK} = -18mA$		-0.9	-1.2		-1.2	V	
			V_{CC} = 4.5V; I_{OH} = –3mA; V_{I} = V_{IL} or V_{IH}	2.5	3.5		2.5		V	
V _{OH}	High-level outpo	ut voltage	V_{CC} = 5.0V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH}	3.0	4.0		3.0		V	
			V_{CC} = 4.5V; I_{OH} = -32mA; V_I = V_{IL} or V_{IH}	2.0	2.6		2.0		V	
V _{OL}	Low-level output	it voltage	V_{CC} = 4.5V; I_{OL} = 64mA; V_{I} = V_{IL} or V_{IH}		0.42	0.55		0.55	V	
V _{RST}	Power-up output low voltage ³		V_{CC} = 5.5V; I_O = 1mA; V_I = GND or V_{CC}		0.13	0.55		0.55	V	
I	Input leakage	Control pins	V _{CC} = 5.5V; V _I = GND or 5.5V		±0.01	±1.0		±1.0	μA	
	current	Data pins	V_{CC} = 5.5V; V_I = GND or 5.5V		5	100		100	μA	
I _{OFF}	Power-off leakage current		$V_{CC} = 0.0V; V_{O} = 4.5V; V_{I} = 0.0V \text{ or } 5.5V$		±5.0	±100		±100	μA	
I _{PU} /I _{PD}	Power-up/down output current ⁴	3-State	V_{CC} = 2.1V; V_{O} = 0.5V; V_{I} = GND or $V_{CC};$ V_{OE} = Don't care		±5.0	±50		±50	μA	
I _{OZH}	3-State output I	High current	V_{CC} = 5.5V; V_{O} = 2.7V; V_{I} = V_{IL} or V_{IH}		5.0	50		50	μA	
I _{OZL}	3-State output L	ow current	V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}		-5.0	-50		-50	μA	
I _{CEX}	Output High lea	kage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	μA	
Ι _Ο	Output current ¹		$V_{CC} = 5.5V; V_{O} = 2.5V$	-50	-80	-180	-50	-180	mA	
I _{CCH}			V_{CC} = 5.5V; Outputs High, V_{I} = GND or V_{CC}		110	250		250	μA	
I _{CCL}	Quiescent supp	ly current	V_{CC} = 5.5V; Outputs Low, V_{I} = GND or V_{CC}		20	30		30	mA	
I _{CCZ}			V_{CC} = 5.5V; Outputs 3-State; V _I = GND or V _{CC}		110	250		250	μA	
ΔI_{CC}	Additional supp input pin ²	ly current per	V_{CC} = 5.5V; one input at 3.4V, other inputs at V_{CC} or GND		0.3	1.5		1.5	mA	

NOTES:

Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
This is the increase in supply current for each input at 3.4V.
For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.
This parameter is valid for any V_{CC} between 0V and 2.1V, with a transition time of up to 10msec. From V_{CC} = 2.1V to V_{CC} = 5V ± 10% a transition time of up to 100µsec is permitted.

AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = 50 \text{pF}$, $R_L = 500 \Omega$

SYMBOL	PARAMETER	WAVEFORM	T _a V	_{amb} = +25° ′cc = +5.0′	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5^{\circ}$	UNIT	
			Min	Тур	Мах	Min	Мах	
f _{MAX}	Maximum clock frequency	1	150	250		150		MHz
t _{PLH} t _{PHL}	Propagation delay CPBA to An, CPAB to Bn	1	2.0 2.5	3.2 3.8	6.6 7.2	2.0 2.5	7.6 8.2	ns
t _{PZH} t _{PZL}	Output enable time OEBA to An, OEAB to Bn	3 4	1.0 2.2	3.2 4.4	4.8 6.2	1.0 2.2	5.8 7.5	ns
t _{PHZ} t _{PLZ}	Output disable time OEBA to An, OEAB to Bn	3 4	2.0 1.5	3.6 2.8	7.6 7.1	2.0 1.5	8.1 7.6	ns

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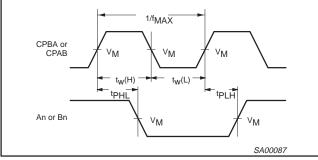
Product specification

AC SETUP REQUIREMENTS

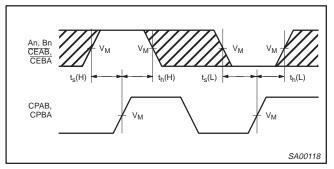
SYMBOL	PARAMETER	WAVEFORM	T _{amb} = +25°C V _{CC} = +5.0V		T _{amb} = −40°C to +85°C V _{CC} = +5.0V ±0.5V	UNIT
			Min	Тур	Min	
t _S (H) t _s (L)	Setup time An to CPAB or Bn to CPBA	2	4.5 3.5	2.2 1.6	4.5 3.5	ns
t _h (H) t _h (L)	Hold time An to CPAB or Bn to CPBA	2	0.0 0.0	-0.8 -1.4	0.0 0.0	ns
t _s (H) t _s (L)	Setup time \overline{CEAB} to CPAB, \overline{CEBA} to CPBA	2	4.0 3.0	0.8 0.8	4.0 3.0	ns
t _h (H) t _h (L)	Hold time CEAB to CPAB, CEBA to CPBA	2	0.0 0.0	-0.7 -0.7	0.0 0.0	ns
t _w (H) t _w (L)	CPAB or CPBA pulse width, High or Low	1	3.0 3.5	0.8 0.9	3.0 3.5	ns

AC WAVEFORMS

 $V_{M} = 1.5V$, $V_{IN} = GND$ to 3.0V

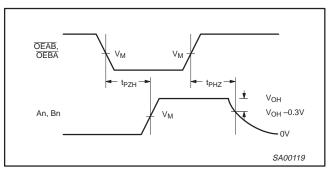


Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency

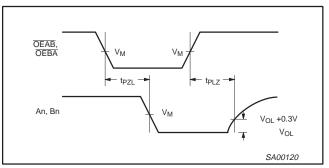


Waveform 2. Data Setup and Hold Times

TEST CIRCUIT AND WAVEFORMS



Waveform 3. 3-State Output Enable Time to High Level and **Output Disable Time from High Level**



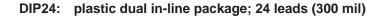
Waveform 4. 3-State Output Enable Time to Low Level and **Output Disable Time from Low Level**

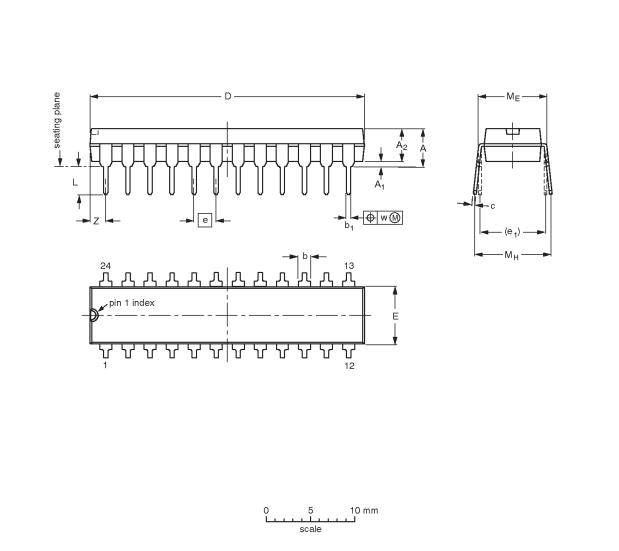
74ABT2952

Octal registered transceiver (3-State)

7 V 500 Ω S1 🔎 From Output Under Test Open ° GND 5 500 Ω C_L = 50 pF ≂ Load Circuit TEST **S**1 t_{pd} open 7 V t_{PLZ}/t_{PZL} t_{PHZ}/t_{PZH} open DEFINITIONS Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value. $C_L =$ SA00012

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DIMENSIONS (millimetre dimensions are derived from the original inch dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	с	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	Μ _E	м _н	w	Z ⁽¹⁾ max.
mm	4.70	0.38	3.94	1.63 1.14	0.56 0.43	0.36 0.25	31.9 31.5	6.73 6.48	2.54	7.62	3.51 3.05	8.13 7.62	10.03 7.62	0.25	2.05
inches	0.185	0.015	0.155	0.064 0.045	0.022 0.017	0.014 0.010	1.256 1.240	0.265 0.255	0.100	0.300	0.138 0.120	0.32 0.30	0.395 0.300	0.01	0.081

Note

1. Plastic or metal protrusions of 0.01 inches maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE			
SOT222-1		MS-001AF			95-03-11			

74ABT2952

SOT222-1

SO24: plastic small outline package; 24 leads; body width 7.5 mm

А Х = v 🕅 A H_E Π v 13 Q (A_3) A₁ pin 1 index Н Н П 日 口 D **1**12 detail X е • 🕈 w 🕅 ⊨l ka bp 5 10 mm 1 scale DIMENSIONS (inch dimensions are derived from the original mm dimensions) А UNIT D⁽¹⁾ E⁽¹⁾ Q z ⁽¹⁾ θ H_E L Lp ۷ Α1 A₂ A_3 bp С е w у max. 0.30 2.45 0.49 0.32 15.6 7.6 10.65 0.9 1.1 1.1 2.65 0.25 0.25 0.25 0.1 mm 1.27 1.4 15.2 0.10 2.25 0.36 0.23 7.4 10.00 0.4 1.0 0.4 8°

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

0.01

0.019

0.014

0.013

0.009

0.61

0.60

0.30

0.29

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT137-1	075E05	MS-013AD				-95-01-24 97-05-22

0.050

0.419

0.394

0.055

0.043

0.039

0.01

0.01

0.004

0.043

0.016

Note

inches

0.012

0.004

0.10

0.096

0.089

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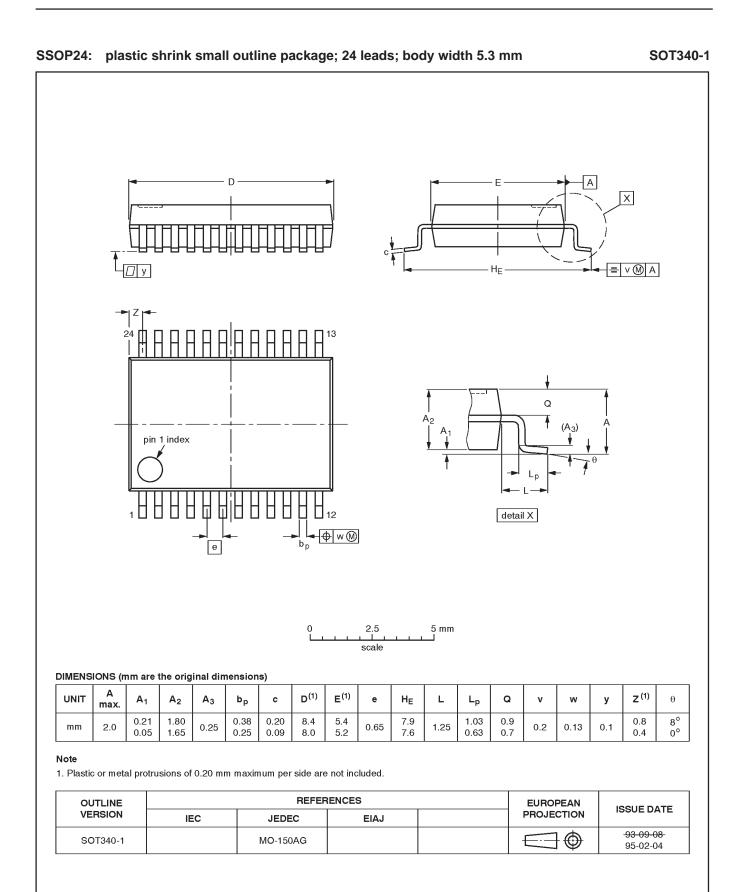
SOT137-1

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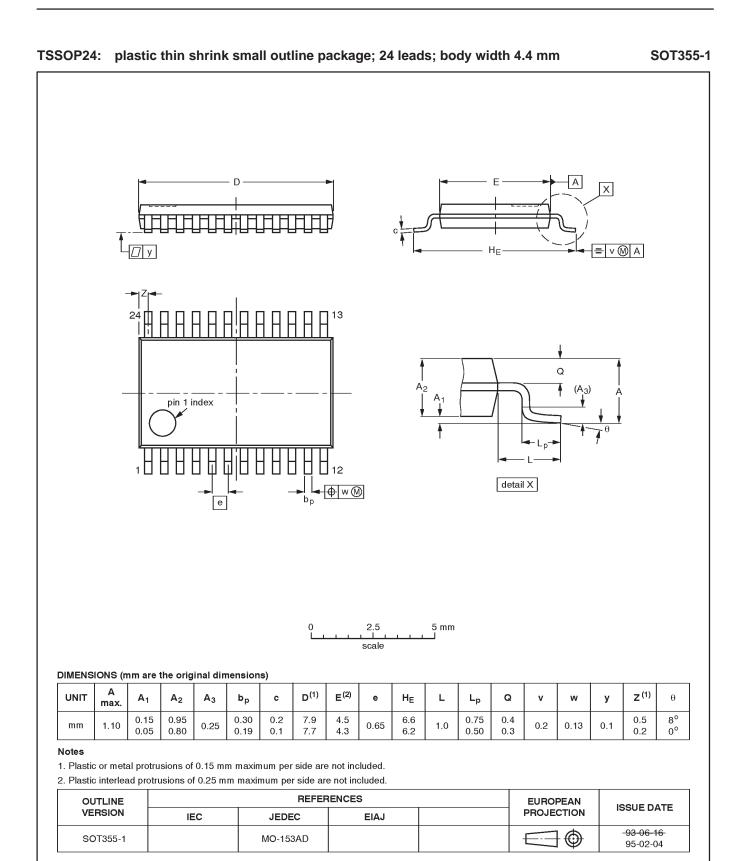
0.035

0.016

74ABT2952



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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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